

**Manufacturer/
Item Name/
Price /**

Scope of application

Technical characteristics

Main competitive advantages

**Lornet
Portable**

**Detector
of Semiconductor
Components**



Used to conduct strategic and search operations in locations and premises, as well as in transport means in order to detect technical devices containing semiconductor components regardless of their functional status (either switched-on or switched-off)

- Probing signal frequency: 890 ÷ 891 MHz. Step 0, 2 MHz
- Signal power in pulse mode: 10 W
- Off-duty factor in pulse mode: 44
- Power of signal in CW mode: 0, 3 W
- Sensitivity of all the receivers: at least -110 dBm (-140 dBW)
- Battery life of replaceable Li-ion rechargeable battery in pulse/ CW signal: at least 5,0 / 2,0 h
- Dimensions in transport/operating condition: 54x15,5x7/102x15,5x5,5 cm
- Full weight of the device in operating condition: less than 1000 g

- Automatic tuning away from narrowband interference;
- Automatic and manual modes of probing signal power changing
- Easy-to-use, small dimensions and low weight of the device
- Use of wireless headphones
- It is possible to operate in hard-to-reach places and under conditions of limited space (antenna thickness does not exceed 18 mm)
- Safe to operate (power density within the operator's zone does not exceed 2,7 mW/cm²)

Lornet-24

**Ultra-compact
Handheld
Detector
of Semiconductor
Components**



Used while conducting strategic and search operations in premises, transport, while human or mail inspection in order to detect special equipment containing semiconductor components regardless of their functional status (either switched-on or switched-off)

- Probing signal frequency range: 2406 ÷ 2414 MHz, Step 2 MHz
- Signal power in pulse mode: 10 W
- Off-duty factor in pulse mode: 44
- Power of CW signal: 0,2 W
- Sensitivity of all the receivers: at least 110 dBm
- Battery life of replaceable Li-ion rechargeable battery in pulse/CW signal: at least 3.0 / 1.5 h
- Dimensions in transport /operating condition: 22x10x7,5/39x10x6,5 cm
- Full weight of the device in operating condition: up to 700 g

- Reliable detection of standard
- SIM-card at a distance of 10-20 cm;
- efficient when detecting frameless recorders of the EDIC type;
- Automatic tuning away from narrowband interference
- Automatic and manual modes of changing probing signal power
- Easy-to-use, tiny dimensions and low weight of the device
- Use of wireless headphones
- Safe to operate (power density within the operator's zone does not exceed 3,8 mW/cm²)

Lornet 36

**Microwave
Detector
of Semiconductor
Components**



• Used while conducting strategic and search operations in premises with high density of electronic equipment in order to detect special equipment containing semiconductor components regardless of their functional status (either switched-on or switched-off).

• Used when conducting strategic and search operations, as well as investigative actions when searching for a SIM-card or inspecting a suspicious object from a safe distance.

- Probing signal frequency range: 3581 ÷ 3608 MHz, Step 13 MHz
- Signal power (off-duty factor) in pulse mode: 18W (160)
- Energy potential (with antenna gain coefficient): 1800 W
- Signal power (off-duty factor) in envelope extraction mode: 12 W (20)
- Sensitivity of all the receivers: at least 110 dBm
- Battery life of replaceable Li-ion rechargeable battery in pulse/ curve extraction mode: at least 3,0/2,0 h
- Weight in operating condition: up to 1400 g

- The world's first non-linear junction detector providing spatial selective detection of targets by a narrow (16 degrees) beam with laser pointer
- Reliable detection of a standard SIM-card at a distance of 1 meter;
- Automatic tuning away from narrowband interference;
- Automatic and manual modes of changing probing signal power
- Use of wireless headphones
- Safe to operate (power density within the operator's zone does not exceed 4,0 mW/cm²)

Lornet 36 mini

Miniature Microwave Detector of Semiconductor Components

New!



Used while conducting strategic and search operations in premises and cars with high density of electronic equipment in order to detect special equipment containing semiconductor components regardless of their functional status (either switched-on or switched-off)

- Probing signal frequency range: 3581 ÷ 3608 MHz, Step 13 MHz
- Signal power (off-duty factor) in pulse mode: 18W (160)
- Energy potential (power of probing signal with antenna gain coefficient): 720 W
- Signal power (off-duty factor) in envelope extraction mode: 12 W (20)
- Sensitivity of all the receivers: at least 110 dBm
- Battery life of replaceable Li-ion rechargeable battery in pulse/ curve extraction mode: at least 3,0/2,0 h
- Weight in operating condition: up to 1000 g

- Non-linear junction detector with spatial selection of target by a narrow (24 degrees) beam with laser pointer
- Reliable detection of a SIM-card at a distance of 60 sm
- Automatic tuning away from narrowband interference
- Automatic and manual modes of changing probing signal power
- Use of wireless headphones
- Safe to operate (power current density in the operator's zone does not exceed 4,0 mW/cm²)

Lornet 0836

Dual-frequency Detector of Semiconductor Components



Used while conducting strategic and search operations as well as investigative actions in premises with efficient search algorithm: quick detection of suspicious semiconductor components and their subsequent spatial localization. Inspecting objects from a safe distance.

- Three types of probing signal:
 - 3581 ÷ 3608 MHz;
 - 789 ÷ 792 MHz;
 - 3581 ÷ 3608 MHz and 789 ÷ 792 MHz simultaneously;
- Signal power (off-duty factor) in pulse mode: 18W (280)
- Energy potential (with antenna gain coefficient): 1800 W
- Signal power (off-duty factor) in curve extraction mode: 6 W (16)
- Sensitivity of all the receivers: at least 110 dBm
- Battery life of a replaceable Li-ion rechargeable battery in pulse/curve extraction mode: at least 2,5/1,5 h
- Weight in operating condition: up to 1000 g

- The world's first dual-frequency non-linear junction detector with spatial selection of target by a narrow (16 degrees) beam with laser pointer
- The option to indicate search results in both frequencies
- Reliable detection of a SIM-card at a distance of 80 cm
- Automatic tuning away from narrowband interference;
- Automatic and manual modes of power change of the probing signal
- Use of wireless headphones
- Safe to operate (power current density within the operator's zone does not exceed 0,3 mW/cm²)

Lornet Star

Spectrum Detector of Semiconductor Components

New!



Used while conducting strategic and search operations in premises and cars, while inspecting mails in order to detect special equipment containing semiconductor components regardless of their functional status (either switched-on or switched-off)

- Easily replaceable transmit/receive blocks for 3 ranges of probing signal frequency
- Probing signal frequency range: 2406 ÷ 2414 MHz, Step 2 MHz
- Probing signal frequency range (optional) 789 ÷ 792 MHz, Step 0,2 MHz
- Probing signal frequency range (optional): 3581 - 3608 MHz, Step 13 MHz
- Spectrum Analyzer at 2nd and 3rd harmonics of probing signal in the band of 10 kHz and a resolution of 40 Hz
- Automatic tuning away from narrowband interference
- Indication of re-emitted signal of the 1st harmonics
- Removable extension rod
- Sensitivity of all the receivers: at least 110 dBm

- The world's first non-linear junction detector with visual analyzing of 2nd and 3rd harmonics spectrum of probing signal, facilitating the distinction between natural and artificial semiconductors
- The use of replaceable transmit/receive units provides the advantages of all three ranges of probing signal:
- 800 MHz - all-weather and relatively low attenuation of signals in dense medium (brick, concrete, etc.);
- 2400 MHz - the opportunity to detect SIM cards and small (about 1 cm²) semiconductor devices;
- 3600 MHz - spatial selection